REVISIONS			
LTR	DESCRIPTION	DATE	APPROVED
A	Update boilerplate to current MIL-PRF-38535 requirements. - PHN	15-01-27	Thomas M. Hess
B	Update boilerplate paragraphs to current VID description requirements. - PHN	21-12-09	Muhammad A. Akbar

CURRENT DESIGN ACTIVITY CAGE CODE 16236
HAS CHANGED NAMES TO:
DLA LAND AND MARITIME
COLUMBUS, OHIO 43218-3990

Prepared in accordance with ASME Y14.24

Vendor item drawing

REV																						
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REV STATUS OF PAGES	**REV**			B	B	B	B	B	B	B	B	B	B									
	PAGE			1	2	3	4	5	6	7	8	9	10									

PMIC N/A	**PREPARED BY** Charles F. Saffle	**DEFENSE SUPPLY CENTER, COLUMBUS** **COLUMBUS, OHIO 43218-3990**
Original date of drawing YY-MM-DD 07-02-21	**CHECKED BY** Charles F. Saffle	**TITLE** MICROCIRCUIT, DIGITAL, CMOS, SINGLE SCHMITT-TRIGGER INVERTER, MONOLITHIC SILICON
	APPROVED BY Thomas M. Hess	
	SIZE **A** / **CODE IDENT. NO.** **16236**	**DWG NO.** **V62/06678**
	REV **B**	**PAGE** 1 **OF** 10

AMSC N/A

5962-V116-21

DISTRIBUTION STATEMENT A. Approved for public release. *Distribution is unlimited.*

1. SCOPE

1.1 Scope. This drawing documents the general requirements of a high performance single Schmitt-trigger inverter microcircuit, with an operating temperature range of -55°C to +125°C.

1.2 Vendor Item Drawing Administrative Control Number. The manufacturer's PIN is the item of identification. The vendor item drawing establishes an administrative control number for identifying the item on the engineering documentation:

V62/06678	-	01	X	A
Drawing number		Device type (See 1.2.1)	Case outline (See 1.2.2)	Lead finish (See 1.2.3)

1.2.1 Device type(s).

Device type	Generic	Circuit function
01	SN74AUC1G14-EP	Single Schmitt-trigger inverter

1.2.2 Case outlines. The case outline(s) are as specified herein.

Outline letter	Number of pins	JEDEC PUB 95	Package style
X	5	MO-178	Plastic small-outline

1.2.3 Lead finishes. The lead finishes are as specified below or other lead finishes as provided by the device manufacturer:

Finish designator	Material
A	Hot solder dip
B	Tin-lead plate
C	Gold plate
D	Palladium
E	Gold flash palladium
F	Tin-lead alloy
Z	Other

1.3 Absolute maximum ratings. 1/

Supply voltage range (V_{CC}) ..... -0.5 V to 3.6 V
Input voltage range (V_I) ..... -0.5 V to 3.6 V 2/
Voltage range applied to any output in the high-impedance
or power-off state (V_O) ..... -0.5 V to 3.6 V 2/
Output voltage range (V_O) ..... -0.5 V to V_{CC} +0.5 V 2/
Input clamp current ($V_I < 0$) (I_{IK}) ..... -50 mA
Output clamp current ($V_O < 0$) (I_{OK}) ..... -50 mA
Continuous output current (I_O) ..... ±20 mA
Continuous current through V_{CC} or GND ..... ±100 mA
Package thermal impedance (θ_{JA}) ..... 206 °C/W 3/
Storage temperature range (T_{STG}) ..... -65°C to 150°C

1.4 Recommended operating conditions. 4/

Supply voltage range (V_{CC}) ..... 0.8 V to 2.7 V
Input voltage range (V_{IN}) ..... 0 V to 3.6 V
Output voltage range (V_O) ..... 0 V to V_{CC}
Maximum high level output current (I_{OH}):
V_{CC} = 0.8 V ..... -0.7 mA
V_{CC} = 1.1 V ..... -3 mA
V_{CC} = 1.4 V ..... -5 mA
V_{CC} = 1.65 V ..... -8 mA
V_{CC} = 2.3 V ..... -9 mA
Maximum low level output current (I_{OL}):
V_{CC} = 0.8 V ..... 0.7 mA
V_{CC} = 1.1 V ..... 3 mA
V_{CC} = 1.4 V ..... 5 mA
V_{CC} = 1.65 V ..... 8 mA
V_{CC} = 2.3 V ..... 9 mA
Operating free-air temperature range (T_A) ..... -55°C to +125°C

1/ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2/ The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
3/ The package thermal impedance is calculated in accordance with JESD 51-7.
4/ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.

2. APPLICABLE DOCUMENTS

JEDEC – SOLID STATE TECHNOLOGY ASSOCIATION (JEDEC)

JEP95	–	Registered and Standard Outlines for Semiconductor Devices
JESD51-7	–	High Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages

(Copies of these documents are available online at https://www.jedec.org).

3. REQUIREMENTS

3.1 Marking. Parts shall be permanently and legibly marked with the manufacturer's part number as shown in 6.3 herein and as follows:

A. Manufacturer's name, CAGE code, or logo
B. Pin 1 identifier
C. ESDS identification (optional)

3.2 Unit container. The unit container shall be marked with the manufacturer's part number and with items A and C (if applicable) above.

3.3 Electrical characteristics. The maximum and recommended operating conditions and electrical performance characteristics are as specified in 1.3, 1.4, and table I herein.

3.4 Design, construction, and physical dimension. The design, construction, and physical dimensions are as specified herein.

3.5 Diagrams.

3.5.1 Case outline. The case outline shall be as shown in 1.2.2 and figure 1.

3.5.2 Function table. The function table shall be as shown in figure 2.

3.5.3 Logic diagram. The logic diagram shall be as shown in figure 3.

3.5.4 Terminal connections. The terminal connections shall be as shown in figure 4.

3.5.5 Test circuit and timing waveforms. The test circuit and timing waveforms shall be as shown in figure 5.

TABLE I. Electrical performance characteristics. 1/

Test	Symbol	Conditions	V_{CC}	Temperature, T_A	Device type	Limits		Unit
						Min	Max	
Positive-going input threshold voltage	V_{T+}		0.8 V	25°C	All	0.5 TYP		V
			1.1 V	25°C, -55°C to 125°C		0.51	0.86	
			1.4 V			0.65	1.00	
			1.65 V			0.79	1.16	
			2.3 V			1.11	1.56	
Negative-going input threshold voltage	V_{T-}		0.8 V	25°C		0.3 TYP		V
			1.1 V	25°C, -55°C to 125°C		0.22	0.53	
			1.4 V			0.30	0.58	
			1.65 V			0.39	0.62	
			2.3 V			0.58	0.87	
Hysteresis voltage (V_{T+} - V_{T-})	ΔV_T		0.8 V	25°C		0.21 TYP		V
			1.1 V	25°C, -55°C to 125°C		0.25	0.38	
			1.4 V			0.31	0.50	
			1.65 V			0.37	0.62	
			2.3 V			0.48	0.77	
High level output voltage	V_{OH}	I_{OH} = -100 μA	0.8 V to 2.7 V	25°C, -55°C to 125°C		V_{CC} – 0.1		V
		I_{OH} = -0.7 mA	0.8 V	25°C		0.55 TYP		
		I_{OH} = -3 mA	1.1 V	25°C, -55°C to 125°C		0.8		
		I_{OH} = -5 mA	1.4 V			1.0		
		I_{OH} = -8 mA	1.65 V			1.2		
		I_{OH} = -9 mA	2.3 V			1.8		
Low level output voltage	V_{OL}	I_{OL} = 100 μA	0.8 V to 2.7 V	25°C, -55°C to 125°C			0.2	V
		I_{OL} = 0.7 mA	0.8 V	25°C		0.25 TYP		
		I_{OL} = 3 mA	1.1 V	25°C, -55°C to 125°C			0.3	
		I_{OL} = 5 mA	1.4 V				0.4	
		I_{OL} = 8 mA	1.65 V				0.45	
		I_{OL} = 9 mA	2.3 V				0.6	

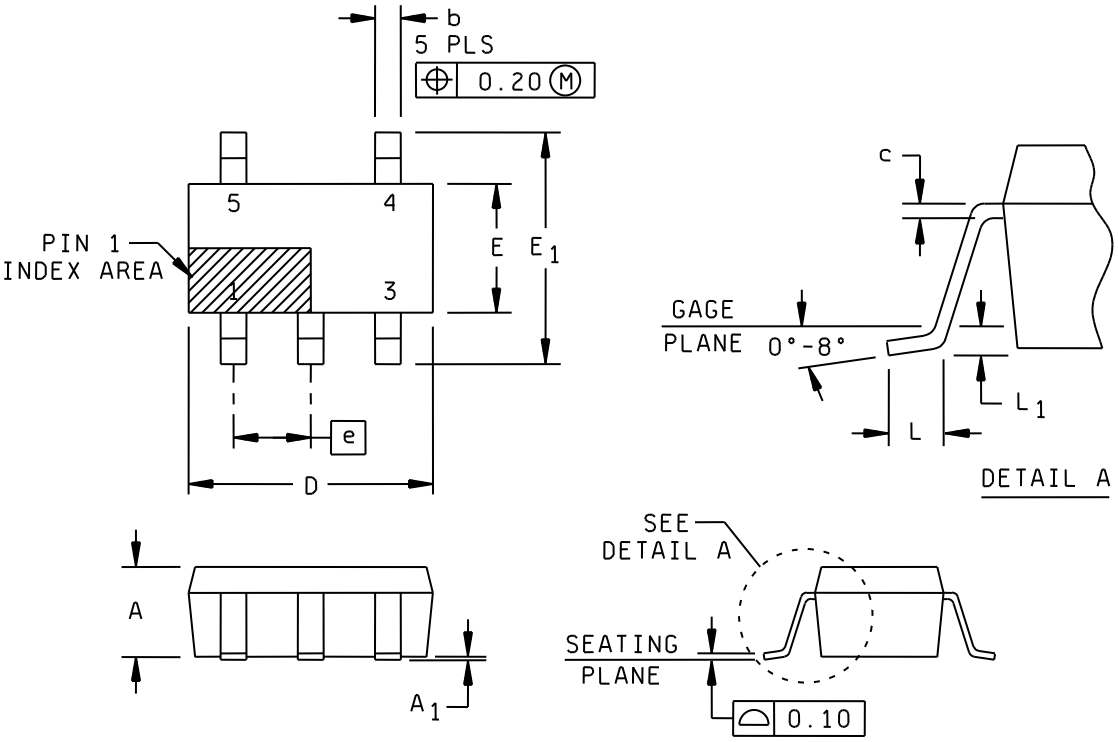
See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued. 1/

Test	Symbol	Conditions	V_{CC}	Temperature, T_A	Device type	Limits		Unit
						Min	Max	
Input current (A input)	I_I	V_I = V_{CC} or GND	0 V to 2.7 V	25°C, -55°C to 125°C	All		±5	µA
Off state leakage current	I_{off}	V_I or V_O = 2.7 V	0 V				±10	µA
Quiescent supply current	I_{CC}	V_I = V_{CC} or GND, I_O = 0	0.8 V to 2.7 V				10	µA
Input capacitance	C_i	V_I = V_{CC} or GND	2.5 V	25°C		3.5 TYP		pF
Power dissipation capacitance	C_{pd}	f = 10 MHz	0.8 V	25°C		14 TYP		pF
			1.2 V			15 TYP		
			1.5 V			15 TYP		
			1.8 V			16 TYP		
			2.5 V			19 TYP		
Propagation delay time, low to high, high to low, A to Y	t_{pd}	C_L = 15 pF, See figure 5.	0.8 V	25°C		5.8 TYP		ns
			1.2 V ±0.1 V	25°C, -55°C to 125°C		0.7	5.5	
			1.5 V ±0.1 V			0.6	4.5	
			1.8 V ±0.15 V			0.5	4.0	
			2.5 V ±0.2 V			0.5	2.0	
		C_L = 30 pF, See figure 5.	1.8 V ±0.15 V	25°C, -55°C to 125°C		0.7	3.0	
			2.5 V ±0.2 V			0.5	3.0	

1/ Testing and other quality control techniques are used to the extent deemed necessary to assure product performance over the specified temperature range. Product may not necessarily be tested across the full temperature range and all parameters may not necessarily be tested. In the absence of specific parametric testing, product performance is assured by characterization and/or design.

Case X



Dimensions									
Symbol	Millimeters		Inches		Symbol	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
A	---	1.45	---	0.057	E	1.45	1.75	0.057	0.069
A1	0.00	0.15	0.000	0.006	E1	2.60	3.00	0.102	0.118
b	0.30	0.50	0.012	0.020	e	0.95 BSC		0.037 BSC	
c	0.08	0.22	0.003	0.009	L	0.30	0.55	0.012	0.022
D	2.75	3.05	0.108	0.120	L1	0.25 BSC		0.010 BSC	

NOTES:
1. All linear dimensions are in millimeters. Inches equivalents are shown for general reference only.
2. This case outline is subject to change without notice.
3. Falls within JEDEC MO-178 variation AA.
4. Body dimensions do not include mold flash or protrusion. Mold flash or protrusion shall not exceed 0.15 millimeters per side.

FIGURE 1. Case outline.

Input A	Output Y
H	L
L	H

H = High voltage level
L = Low voltage level

FIGURE 2. Function table.

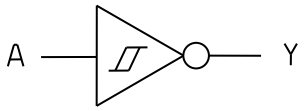
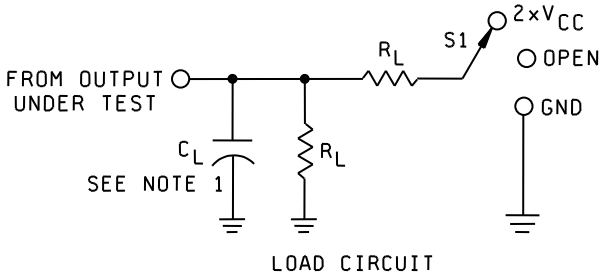


FIGURE 3. Logic diagram.

Device type:	All
Case outline:	X
Terminal number	Terminal symbol
1	NC
2	A
3	GND
4	Y
5	V_{CC}

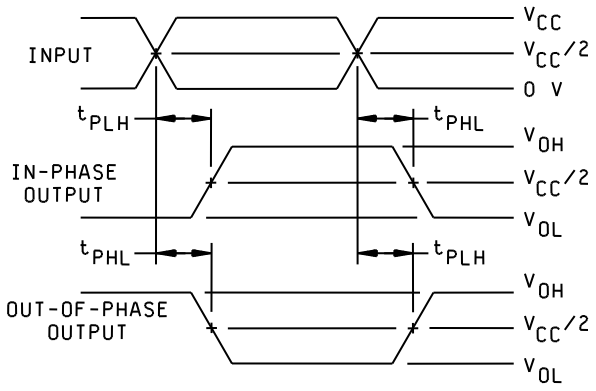
NC = No connection

FIGURE 4. Terminal connections.



TEST	S1
t_{PLH}/t_{PHL}	OPEN

V_{CC}	C_L	R_L
0.8 V	15 pF	2 kΩ
1.2 V ±0.1 V	15 pF	2 kΩ
1.5 V ±0.1 V	15 pF	2 kΩ
1.8 V ±0.15 V	15 pF	2 kΩ
2.5 V ±0.2 V	15 pF	2 kΩ
1.8 V ±0.15 V	30 pF	1 kΩ
2.5 V ±0.2 V	30 pF	500Ω



NOTES:
1. C_L includes probe and jig capacitance.
2. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, input slew rate ≥ 1 V/ns.
3. The outputs are measured one at a time with one input transition per measurement.
4. t_{PLH} and t_{PHL} are the same as t_{pd}.

FIGURE 5. Test circuit and timing waveforms.

4. VERIFICATION

4.1 Product assurance requirements. The manufacturer is responsible for performing all inspection and test requirements as indicated in their internal documentation. Such procedures should include proper handling of electrostatic sensitive devices, classification, packaging, and labeling of moisture sensitive devices, as applicable.

5. PREPARATION FOR DELIVERY

5.1 Packaging. Preservation, packaging, labeling, and marking shall be in accordance with the manufacturer's standard commercial practices for electrostatic discharge sensitive devices.

6. NOTES

6.1 ESDS. Devices are electrostatic discharge sensitive and are classified as ESDS class 1 minimum.

6.2 Configuration control. The data contained herein is based on the salient characteristics of the device manufacturer's data book. The device manufacturer reserves the right to make changes without notice. This drawing will be modified as changes are provided.

6.3 Suggested source(s) of supply. Identification of the suggested source(s) of supply herein is not to be construed as a guarantee of present or continued availability as a source of supply for the item. DLA Land and Maritime maintains an online database of all current sources of supply at https://landandmaritimeapps.dla.mil/programs/smcr/.

Vendor item drawing administrative control number 1/	Device manufacturer CAGE code	Vendor part number	Top side marking 2/
V62/06678-01XE	01295	SN74AUC1G14MDBVREP	U14_

1/ The vendor item drawing establishes an administrative control number for identifying the item on the engineering documentation.
2/ The actual top-side marking has one additional character that designates the assembly/test site.

CAGE code	Source of supply
01295	Texas Instruments, Inc. Semiconductor Group 8505 Forest Lane P.O. Box 660199 Dallas, TX 75243